

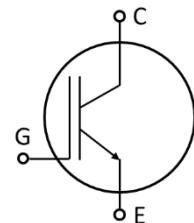
IGBT Chip

Features:

- 1200V Trench & Field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Applications:

- Inverter
- Welding machine
- Induction heating



Mechanical parameters

Die size	9.876 × 9.880	mm ²
Emitter pad size	See chip drawing	
Gate pad size	1.0839 × 1.0449	
Area total	97.57	
Thickness	120	μm
Wafer size	200	mm
Max. possible chips per wafer	255	
Passivation front side	Polyimide	
Pad metal	AlCu with Ti/TiN (4μm & 300A/1000A)	
Backside metal	Al/Ti/Ni/Ag	

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage	V _{CE}	1200	V
DC collector current	I _C	100	A
Operating junction temperature	T _j	-40 ... +175	°C
Gate emitter voltage	V _{GE}	±20	V
Short circuit data	t _{sc}	10	μs

Static Characteristics (tested on wafer), $T_{vj}=25^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			Min.	Typ.	Max.	
Collector-Emitter breakdown voltage	$V_{(\text{BR})\text{CES}}$	$V_{\text{GE}}=0\text{V}, I_{\text{C}}=1\text{mA}$	1200			V
Collector-Emitter saturation voltage	V_{CEsat}	$V_{\text{GE}}=15\text{V}, I_{\text{C}}=100\text{A}$		2.07	2.47	
Gate-Emitter threshold voltage	$V_{\text{GE}(\text{th})}$	$I_{\text{C}}=3.8\text{mA}, V_{\text{GE}}= V_{\text{CE}}$	5.2	5.8	6.4	
Zero gate voltage collector current	I_{CES}	$V_{\text{CE}}=1200\text{V}, V_{\text{GE}}= 0\text{V}$			10	uA
Gate-Emitter leakage current	I_{GES}	$V_{\text{CE}}=0\text{V}, V_{\text{GE}}= 20\text{V}$			100	nA
Integrated gate resistor	r_G ^{a)}			8.23		Ω
Input capacitance	C_{ies} ^{a)}	$V_{\text{CE}}=25\text{V}, V_{\text{GE}}=0\text{V},$ $f=100\text{kHz}$		5.48		nF
Reverse transfer capacitance	C_{res} ^{a)}			0.22		

^{a)} tested on device

Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	
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Chip Drawing